

Migration from S34MS-1 to S34MS-2

AN200508 details how to migrate designs from SkyHigh S34MS-1 (S34MS01G1, S34MS02G1, S34MS04G1, and S34MS08G1) NAND flash memory devices to SkyHigh S34MS-2 (S34MS01G2, S34MS02G2, S34MS04G2, and S34MS08G2) NAND flash memory devices.

1 Introduction

This application note details how to migrate designs from SkyHigh S34MS-1 (S34MS01G1, S34MS02G1, S34MS04G1, and S34MS08G1) NAND flash memory devices to SkyHigh S34MS-2 (S34MS01G2, S34MS02G2, S34MS04G2, and S34MS08G2) NAND flash memory devices. The S34MS-1 devices are 1.8 volt NAND flash memory manufactured with 4x nm technology. The S34MS-2 devices are 1.8 volt NAND flash memory manufactured with 32 nm technology node.

Note: All the information provided in this guide illustrates only the differences for each section. Refer to the respective data sheets for more information.

SkyHigh S34MS 4x NAND flash family devices are compatible with the SkyHigh 32 nm NAND flash memory devices with respect to:

- Block, page, and byte size architecture
- JEDEC standard-compliant software command set

Note: The spare area for 32 nm, x8, 2 Gb / 4 Gb / 8 Gb is 128 bytes instead of 64 bytes. The spare area for 32 nm, x16, 2 Gb / 4 Gb is 64 words instead of 32 words.

2 Feature Comparison

Most of the features between S34MS-1 and S34MS-2 are similar, as shown in Table 1. Refer to the respective S34MS-1 and S34MS-2 data sheets to verify any other features.

Features	48 nm / 41 nm	32 nm		
Page Size	2 kB	2 kB		
Number of Pages per Block	64	64		
Number of Blocks	1024 for every 1Gb	1024 for every 1Gb		
Densities	1 Gb / 2 Gb / 4 Gb / 8 Gb (DDP)	1 Gb / 2 Gb / 4 Gb / 8 Gb (DDP)		
Interface	ONFI 1.0	ONFI 1.0		
t _R	25 µs	25 µs (1 Gb) 30 µs (2 Gb / 4 Gb / 8 Gb)		
Sequential Access	45 ns	45 ns		
t _{PROG}	250 µs	300 µs		
t _{BERS}	2 ms (1 Gb) 3.5 ms (2 Gb / 4 Gb / 8 Gb)	3 ms (1 Gb) 3.5 ms (2 Gb / 4 Gb / 8 Gb)		
Spare Area per Page Size	64B / 2 kB (All densities)	64B / 2 kB (1 Gb) 128B / 2 kB (2 Gb / 4 Gb / 8 Gb)		
ECC Requirement 1-bit / 512 + 16 bytes		4-bi t / 512 + 16 bytes (1 Gb) 512 + 32 bytes (2 Gb / 4 Gb / 8 Gb)		
Cycling (Typical)	cling (Typical) 100K			
Retention (Typical)	ention (Typical) 10-year 10-year			
v _{cc}	1.8V	1.8V		

Table 1. Feature Comparison (Sheet 1 of 2)



Table 1. Feature Comparison (Sheet 2 of 2)

Features	48 nm / 41 nm	32 nm		
I/O Bus Width	x8 and x16	x8 and x16		
Secure Block Feature	OTP (1 Block) (1)	OTP (1 Block)		
Reset after Power-up	Not required	Not required		
Packages	48-Pin TSOP / 63-Ball BGA	48-Pin TSOP / 63-Ball BGA / 67-Ball BG		
Read Uniquie ID	Not supported	Supported		

Note:

1. For 41 nm only.

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AC Specification

The S34MS-1 and S34MS-2 have primarily compatible specifications. Differences in AC Characteristics between the devices are highlighted in Table 2. The potential impact of any parameter specification differences should be evaluated and validated. Refer to the respective S34MS-1 and S34MS-2 data sheets to verify the most up to date specifications.

Table 2. AC Characteristics

Parameter	Symbol	S34MS-1			S34MS-2		
Falameter	Symbol	Min	Max	Unit	Min	Max	Unit
CE# high to output High-Z	t		30	ns	_	50 (1 Gb)	ns
	t _{CHZ}		50	115	_	30 (2 / 4 Gb)	115
Data transfer from cell to	to 🔒		— 25	μs	_	25 (1 Gb)	110
register	t _R					30 (2 / 4 / 8 Gb)	μs

Table 3. AC Test Conditions

	Parameter	S34MS-1	S34MS-2
Output load (1	.7V-1.95V) 1 TTL Gate and CL	30 pF	30 pF

4 DC Specification

The S34MS-1 and S34MS-2 have primarily compatible specifications. Differences in DC Characteristics between the devices are highlighted in Table 4. The potential impact of any parameter specification differences should be evaluated and validated. Refer to the respective S34MS-1 and S34MS-2 data sheets to verify the most up to date specifications.

Parameter Symbo		Test Conditions	S34MS-1				S34MS-2			
		Test conditions	Min	Тур	Мах	Units	Min	Тур	Мах	Units
Dower On		Power-Up Current	_	15 (2 Gb/4 Gb)	30	mA				
Power-On Current I _{CC0}		FFh command input after power on						_	50 per device	mA
Sequential Read Current	I _{CC1}			10	20	mA	_	15	30	mA
Program		Normal	_	10	20	mA	_	15	30	mA
Current '	I _{CC2}	Cache	_	15	30	mA		15	30	mA
Erase Current	I _{CC3}	_		10	20	mA		15	30	mA



5 Device ID

This section provides a comparison between S34MS-1 and S34MS-2 flash memory Device ID.

	S34MS-1							
Density	Org	1st	2nd	3rd	4th	5th		
1 Gb		01h	A1h	00h	15h	—		
2 Gb	x8	01h	AAh	90h	15h	44h		
4 Gb	-	01h	ACh	90h	15h	54h		
1 Gb		01h	B1h	00h	55h	—		
2 Gb	x16	01h	BAh	90h	55h	44h		
4 Gb	-	01h	BCh	90h	55h	54h		
	S34MS-2							
Density	Org	1st	2nd	3rd	4th	5th		
1 Gb		01h	A1h	80h	15h	—		
2 Gb	¥9	01h	AAh	90h	15h	46h		
4 Gb	x8	01h	ACh	90h	15h	56h		
8 Gb (1)		01h	A3h	D1h	15h	5Ah		
1 Gb		01h	B1h	80h	55h	—		
2 Gb	x16	01h	BAh	90h	55h	46h		
4 Gb		01h	BCh	90h	55h	56h		

Table 5. Manufacture/Device ID

Note:

1. 4 Gb x 2 – DDP with one CE#.

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References

- SkyHigh SLC NAND Flash Memory for Embedded Data Sheet, Publication Number S34MS01G1_4G1
- SkyHigh SLC NAND Flash Memory for Embedded Data Sheet, Publication Number S34MS01G2_4G2
- S34MS08G2 NAND Flash Memory for Embedded Data Sheet, Publication Number S34MS08G2



Document History Page

Document Title: AN200508 - Migration from S34MS-1 to S34MS-2 Document Number: 002-00508							
Rev.	ECN No.	Orig. of Change	Submission Date	Description of Change			
**	_	-	12/11/2014	Initial version.			
*A	4977228	MSWI	10/20/2015	Updated to Cypress template.			
*В	5869109	AESATMP8	08/31/2017	Updated logo and Copyright.			
*C	6403803	MNAD	12/06/2018	Updated to new template. Completing Sunset Review.			
*D		MNAD	05/31/2017	Updated to SkyHigh format.			